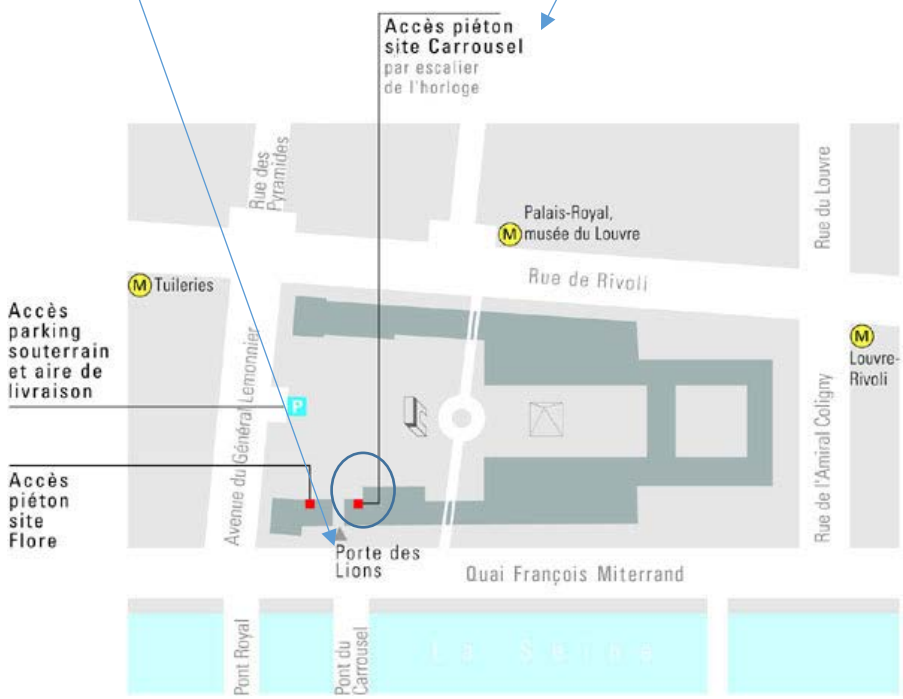
RADIATE Summer School and IBA Tutorial Information Sheet

Dates :	Summer School	Thursday 10 and Friday 11 October 2019
	Tutorial	Saturday 12 October 2019

Venue : CR2MF Auditorium, Palais du Louvre

Access : There will be signs from the Clocktower Staircase just inside the Lions Gate. Best metro is line 2, Palais Royal – Musée du louvre



<u>Access to the Auditorium will be available from 08h30</u> each morning. You will be issued badges by the security personnel at the entrance.

Coffee breaks and lunch will be served on site, next to the Auditorium.

Programme

RADIATE Summer School and IBA Conference Tutorial 10-12 October 2019, Palais du Louvre, Paris		
Thursday 10 October 2019		
9h15 - 9h30	**Opening and Introduction**	Ian Vickridge INSP, Sorbonne Université, Paris (FR)
9h30 - 11h00	**Collisions**	Ian Vickridge INSP, Sorbonne Université, Paris (FR)
11h00	coffee	
11h30	**Stopping Power and Straggling**	Ian Vickridge INSP, Sorbonne Université, Paris (FR)
13h00	Lunch	
14h30	**Collisions of fast ions with atoms**	Johnny Feraz-Diaz UFRGS, Porto Alegre (BR)
16hoo	coffee	
16h30	**Participant Presentations** (5min each)	
18h00	End	
18h20	Leave for dinner at Lycée Jean Drouant	
Friday 11 October 2019		
9h00	**RBS/EBS and ERDA**	Iva Bogdanović Radović RBI, Zagreb (CR)
10h30	Coffee	
11h00	**PIXE**	Thomas Calligaro C2RMF, Paris (FR)
12h30	Lunch	
13h30	**NRA and PIGE**	Hicham Khodja LEEL, CEA Saclay (FR)
15h00	coffee	
15h30	**Participant Presentations (5min each)**	5 min each
17h00	**Uncertainty, Precision and Accuracy in IBA**	Chris Jeynes Univ. Surrey IBC, Guildford (UK)
18h30	End	
RADIATE + IBA Tutorial Saturday 12 October 2019		
Saturday		
9h00	**IBA Applications to Cultural Heritage**	Claire Pacheco C2RMF, Paris (Fr)
10h30	Coffee	
10h45	**ERDA, the most powerful ion beam technique in materials science**	Timo Sajavaara University of Jyväskylä (FI)
12h15	Lunch	
14h00	**The power (and limitations) of ion beam analysis in materials science**	Andre Vantomme KU Leuven (BE)
15h30	Coffee	
15h45	**Thin film depth profiling by ion beam analysis: a comparison to other analytical techniques**	Julien Colaux Unamur (BE)
16h15	End	